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1. Global joint venture starts operations as WeEn Semiconductors

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WeEn Semiconductors



BT151-500L

SCR, 12 A, 5mA, 500 V, SOT78

Rev. 05 — 2 March 2009

Product data sheet

1. Product profile

1.1 General description

Planar passivated SCR (Silicon Controlled Rectifier) in a SOT78 plastic package.

1.2 Features and benefits

- High reliability
- High surge current capability
- High thermal cycling performance

1.3 Applications

- Ignition circuits
- Motor control

- Protection Circuits
- Static switching

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	-	500	V
$I_{T(AV)}$	average on-state current	half sine wave; T _{mb} ≤ 109 °C; see <u>Figure 3</u>	-	-	7.5	Α
I _{T(RMS)}	RMS on-state current	half sine wave; $T_{mb} \le 109 ^{\circ}\text{C}$; see Figure 1; see Figure 2	-	-	12	Α
Static ch	aracteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V}; T_j = 25 \text{ °C};$ $I_T = 100 \text{ mA}; \text{ see } \frac{\text{Figure 8}}{\text{MH}}$	-	2	5	mA



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SCR, 12 A, 5mA, 500 V, SOT78

Pinning information

Table 2. **Pinning information**

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	K	cathode		N.1
2	Α	anode	mb	А Д К
3	G	gate	205	G sym037
mb	mb	anode	1 2 3	
			SOT78 (TO-220AB;SC-46)	

Ordering information 3.

Table 3. **Ordering information**

Product data sheet

Type number	Package		
	Name	Description	Version
BT151-500L	TO-220AB; SC-46	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	500	V
V_{RRM}	repetitive peak reverse voltage		-	500	V
I _{T(AV)}	average on-state current	half sine wave; T _{mb} ≤ 109 °C; see <u>Figure 3</u>	-	7.5	Α
I _{T(RMS)}	RMS on-state current	half sine wave; $T_{mb} \le 109 \text{ °C}$; see Figure 1; see Figure 2	-	12	Α
dI _T /dt	rate of rise of on-state current	I_T = 20 A; I_G = 50 mA; dI_G/dt = 50 mA/ μ s	-	50	A/μs
I _{GM}	peak gate current		-	2	Α
P _{GM}	peak gate power		-	5	W
T _{stg}	storage temperature		-40	150	°C
Tj	junction temperature		-	125	°C
I _{TSM}	non-repetitive peak	half sine wave; $t_p = 8.3 \text{ ms}$; $T_{j(init)} = 25 \text{ °C}$	-	132	Α
	on-state current	half sine wave; $t_p = 10$ ms; $T_{j(init)} = 25$ °C; see Figure 4; see Figure 5	-	120	Α
I ² t	I2t for fusing	t _p = 10 ms; sine-wave pulse	-	72	A ² s
$P_{G(AV)}$	average gate power	over any 20 ms period	-	0.5	W
V _{RGM}	peak reverse gate voltage		-	5	V

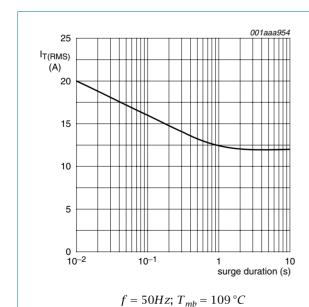


Fig 1. RMS on-state current as a function of surge duration; maximum values

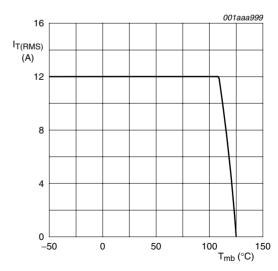


Fig 2. RMS on-state current as a function of mounting base temperature; maximum values

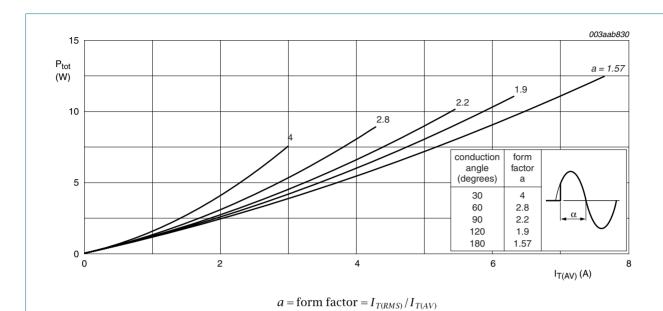


Fig 3. Total power dissipation as a function of average on-state current; maximum values

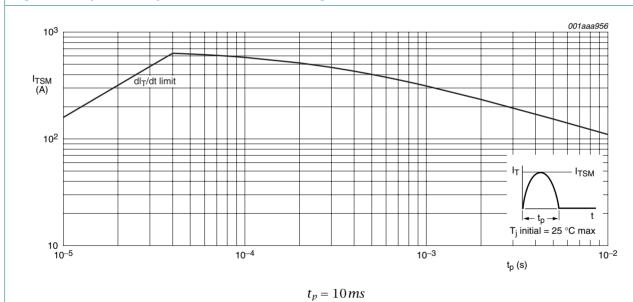


Fig 4. Non-repetitive peak on-state current as a function of pulse width for sinusoidal currents; maximum values

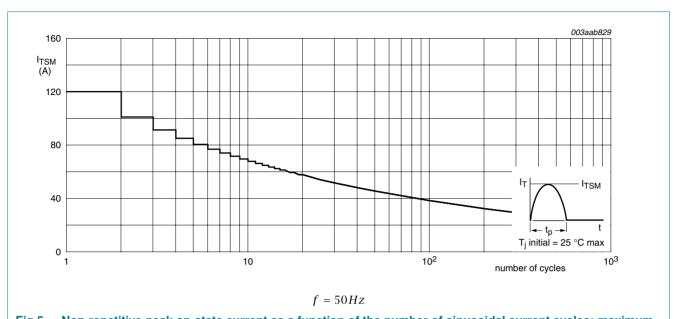
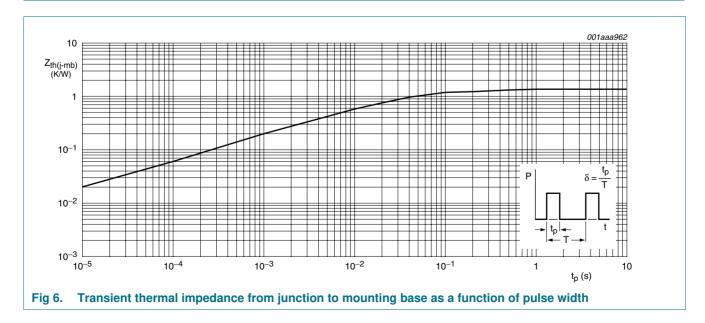


Fig 5. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	see Figure 6	-	-	1.3	K/W
R _{th(j-a)}	thermal resistance from junction to ambient free air		-	60	-	K/W



6. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
I _{GT}	gate trigger current	V_D = 12 V; T_j = 25 °C; I_T = 100 mA; see Figure 8	-	2	5	mA
IL	latching current	$V_D = 12 \text{ V}; T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 9}}{}$	-	10	40	mA
I _H	holding current	$V_D = 12 \text{ V}; T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 10}}{\text{ or } 10}$	-	7	20	mA
V _T	on-state voltage	$I_T = 23 \text{ A}; T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 11}}{\text{Figure 11}}$	-	1.4	1.75	V
V_{GT}	gate trigger voltage	I_T = 100 mA; V_D = 12 V; T_j = 25 °C; see Figure 12	-	0.6	1.5	V
		$I_T = 100 \text{ mA}; V_D = 500 \text{ V}; T_j = 125 \text{ °C}$	0.25	0.4	-	V
I_D	off-state current	$V_D = 500 \text{ V}; T_j = 125 ^{\circ}\text{C}$	-	0.1	0.5	mΑ
I _R	reverse current	$V_R = 500 \text{ V}; T_j = 125 ^{\circ}\text{C}$	-	0.1	0.5	mA
Dynamic o	characteristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 335 V; T_j = 125 °C; exponential waveform; gate open circuit	50	130	-	V/µs
		V_{DM} = 335 V; T_j = 125 °C; R_{GK} = 100 Ω ; exponential waveform; see Figure 7	200	1000	-	V/µs
t _{gt}	gate-controlled turn-on time	$I_{TM} = 40 \text{ A}; V_D = 500 \text{ V}; I_G = 100 \text{ mA}; \\ dI_G/dt = 5 \text{ A}/\mu \text{s}; T_j = 25 \text{ °C}$	-	2	-	μs
t _q	commutated turn-off time	$V_{DM} = 335 \text{ V}; T_j = 125 \text{ °C}; I_{TM} = 20 \text{ A};$ $V_R = 25 \text{ V}; (dI_T/dt)_M = 30 \text{ A/}\mu\text{s};$ $dV_D/dt = 50 \text{ V/}\mu\text{s}; R_{GK} = 100 \Omega$	-	70	-	μѕ

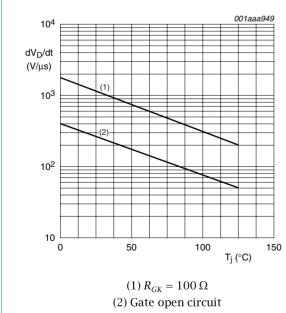


Fig 7. Critical rate of rise of off-state voltage as a function of junction temperature; minimum values

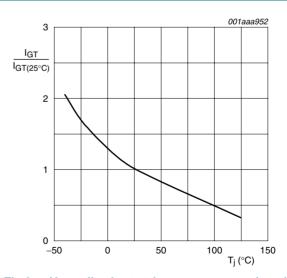


Fig 8. Normalized gate trigger current as a function of junction temperature

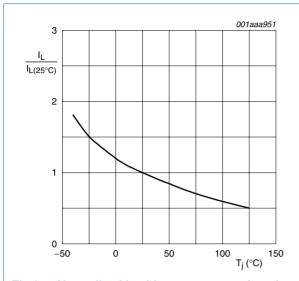


Fig 9. Normalized latching current as a function of junction temperature

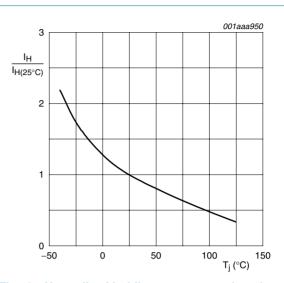
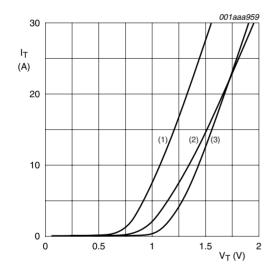


Fig 10. Normalized holding current as a function of junction temperature



 $V_0 = 1.06 \ V; \ R_s = 0.0304 \ \Omega$ (1) $T_j = 150 \ ^{\circ}C;$ typical values (2) $T_j = 150 \ ^{\circ}C;$ maximum values (3) $T_j = 25 \ ^{\circ}C;$ maximum values

Fig 11. On-state current as a function of on-state voltage

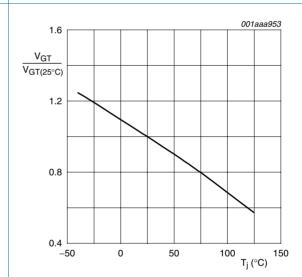


Fig 12. Normalized gate trigger voltage as a function of junction temperature

7. Package outline

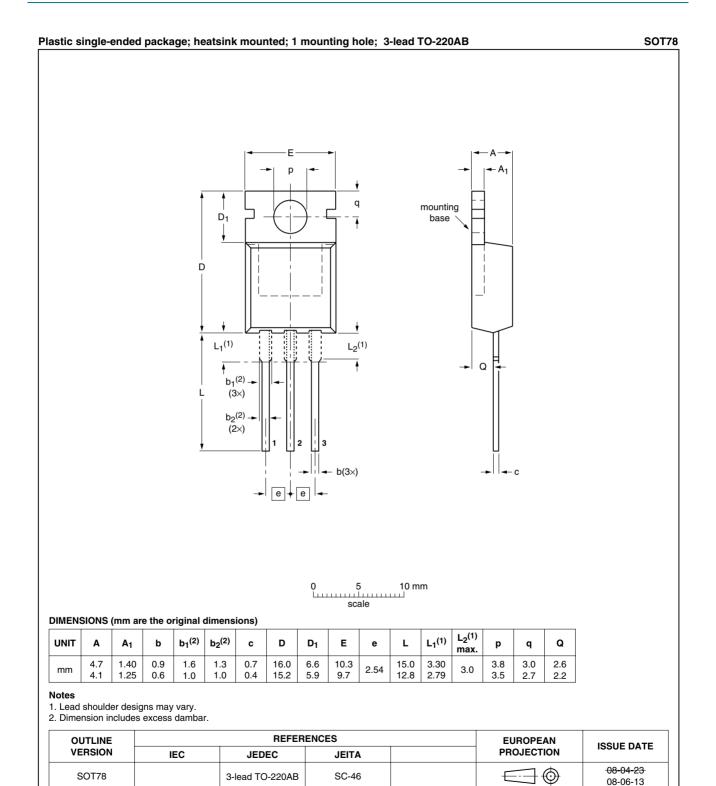


Fig 13. Package outline SOT78 (TO-220AB)

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SCR, 12 A, 5mA, 500 V, SOT78

Revision history

Table 7. **Revision history**

Product data sheet

		Data sheet status	Change notice	Supersedes
BT151-500L 5 200	090302			
-	000002	Product data sheet	-	BT151_SER_L_R_4
Modifications:	Package outl	ine updated.		
•	Type number	BT151-500L separated fr	om data sheet BT151_SE	ER_L_R_4.
BT151_SER_L_R_4 200	061023	Product data sheet	-	BT151_SERIES_3
BT151_SERIES_3 (9397 200 750 13159)	040607	Product specification	-	BT151_SERIES_2
BT151_SERIES_2 199	990601	Product specification	-	BT151_SERIES_1
BT151_SERIES_1 199	970901	Product specification	-	-

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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